2:1 Mux/Demux Analog Switches

The NLAS1053 is an advanced CMOS analog switch fabricated with silicon gate CMOS technology. It achieves very high speed propagation delays and low ON resistances while maintaining CMOS low power dissipation. The device consists of a single 2:1 Mux/Demux (SPDT), similar to ON Semiconductor's NLAS4053 analog and digital voltages that may vary across the full power supply range (from V_{CC} to GND).

The inhibit and select input pins have over voltage protection that allows voltages above V_{CC} up to 7.0 V to be present without damage or disruption of operation of the part, regardless of the operating voltage.

Features

- High Speed: $t_{PD} = 1$ ns (Typ) at $V_{CC} = 5.0$ V
- Low Power Dissipation: $I_{CC} = 2 \mu A$ (Max) at $T_A = 25^{\circ}C$
- High Bandwidth, Improved Linearity, and Low RDS_{ON}
- INH Pin Allows a Both Channels 'OFF' Condition (With a High)
- $RDS_{ON} \cong 25 \Omega$, Performance Very Similar to the NLAS4053
- Break Before Make Circuitry, Prevents Inadvertent Shorts
- Useful For Switching Video Frequencies Beyond 50 MHz
- Latchup Performance Exceeds 300 mA
- ESD Performance: HBM > 2000 V; MM > 200 V, CDM > 1500 V
- Tiny US8 Package, Only 2.1 X 3.0 mm
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

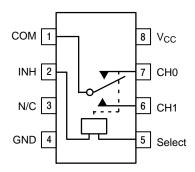
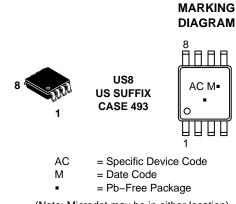


Figure 1. Pin Assignment



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(Note: Microdot may be in either location)

FUNCTION TABLE

INH	Select	Ch 0	Ch 1
н	Х	OFF	OFF
L	L	ON	OFF
L	Н	OFF	ON

ORDERING INFORMATION

Device	Package	Shipping [†]
NLAS1053USG	US8 (Pb–Free)	3000 / Tape & Reel

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Positive DC Supply Voltage		-0.5 to +7.0	V
Digital Input Voltage (Select and Inhibit)	V _{IN}	$-0.5 \leq V$ is $\leq +7.0$	V
Analog Output Voltage (V _{CH} or V _{COM})	V _{IS}	$-0.5 \leq V$ is $\leq V_{CC}$ +0.5	V
DC Current, Into or Out of Any Pin	I _{IK}	50	mA
Storage Temperature Range	T _{STG}	-65 to +150	°C
Lead Temperature, 1 mm from Case for 10 Seconds	TL	260	°C
Junction Temperature under Bias	TJ	+150	°C
Thermal Resistance	θ_{JA}	250	°C/W
Power Dissipation in Still Air at 85°C	PD	250	mW
Moisture Sensitivity	MSL	Level 1	
Flammability Rating Oxygen Index: 30	% – 35% F _R	UL 94 V–0 @ 0.125 in	
ESD Withstand Voltage Human Body Mode Machine Mode Charged Device Mode	(Note 3)	> 2000 200 N/A	V
Latchup Performance Above V _{CC} and Below GND at 85°C	(Note 5) I _{Latchup}	±300	mA

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Measured with minimum pad spacing on an FR4 board, using 10 mm-by-1 inch, 2-ounce copper trace with no air flow.

2. Tested to EIA/JESD22-A114-A.

3. Tested to EIA/JESD22-A115-A.

4. Tested to JESD22–C101–A.

5. Tested to EIA/JESD78.

RECOMMENDED OPERATING CONDITIONS

Characteristics		Symbol	Min	Max	Unit
Positive DC Supply Voltage		V _{CC}	2.0	5.5	V
Digital Input Voltage (Select and Inhibit)		V _{IN}	GND	5.5	V
Static or Dynamic Voltage Across an Off Switch		V _{IO}	GND	V _{CC}	V
Analog Input Voltage (CH, COM)		V _{IS}	GND	V _{CC}	V
Operating Temperature Range, All Package Types		T _A	-55	+125	°C
Input Rise or Fall Time (Enable Input)		t _r , t _f	0 0	100 20	ns/V

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

DEVICE JUNCTION TEMPERATURE VERSUS TIME TO 0.1% BOND FAILURES

Junction Temperature °C	Time, Hours	Time, Years
80	1,032,200	117.8
90	419,300	47.9
100	178,700	20.4
110	79,600	9.4
120	37,000	4.2
130	17,800	2.0
140	8,900	1.0

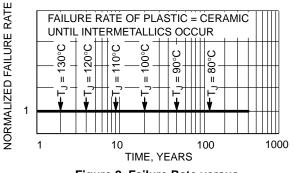


Figure 2. Failure Rate versus Time Junction Temperature

DC CHARACTERISTICS – Digital Section (Voltages Referenced to GND)

				Guaranteed Limit			
Parameter	Condition	Symbol	V _{cc}	-55°C to 25°C	<85°C	<125°C	Unit
Minimum High–Level Input Voltage, Select and Inhibit Inputs		V _{IH}	2.0 2.5 3.0 4.5 5.5	1.5 1.9 2.1 3.15 3.85	1.5 1.9 2.1 3.15 3.85	1.5 1.9 2.1 3.15 3.85	V
Maximum Low–Level Input Voltage, Select and Inhibit Inputs		VIL	2.0 2.5 3.0 4.5 5.5	0.5 0.6 0.9 1.35 1.65	0.5 0.6 0.9 1.35 1.65	0.5 0.6 0.9 1.35 1.65	V
Maximum Input Leakage Current, Select and Inhibit Inputs	$V_{IN} = 5.5 V \text{ or GND}$	I _{IN}	0 V to 5.5 V	±0.1	±1.0	±1.0	μΑ
Maximum Quiescent Supply Current	Select and Inhibit = V_{CC} or GND	Icc	5.5	1.0	1.0	2.0	μΑ

DC ELECTRICAL CHARACTERISTICS – Analog Section

				Guara	nteed Limit	t	
Parameter	Condition	Symbol	V _{cc}	–55 to 25°C	< 85°C	< 125°C	Unit
Maximum "ON" Resistance (Figures 17 – 23)	$ \begin{array}{l} V_{IN} = V_{IL} \text{ or } V_{IH} \\ V_{IS} = GND \text{ to } V_{CC} \\ I_{IN}I \leq 10.0 \text{ mA} \end{array} $	R _{ON}	2.5 3.0 4.5 5.5	70 40 20 16	85 46 28 22	105 52 34 28	Ω
ON Resistance Flatness (Figures 17 – 23)	$ \begin{array}{l} V_{IN} = V_{IL} \mbox{ or } V_{IH} \\ I_{IN}I \leq 10.0 \mbox{ mA} \\ V_{IS} = 1V, 2V, 3.5V \end{array} $	R _{FLAT} (ON)	4.5	4	4	5	Ω
ON Resistance Match Between Channels	$\begin{array}{l} V_{IN} = V_{IL} \mbox{ or } V_{IH} \\ I_{IN}I \leq 10.0 \mbox{ mA} \\ V_{CH1} \mbox{ or } V_{CH0} = 3.5 \mbox{ V} \end{array}$	ΔR _{ON} (ON)	4.5	2	2	3	Ω
CH1 or CH0 Off Leakage Current (Figure 9)		I _{CH0} I _{CH1}	5.5	1	10	100	nA
COM ON Leakage Current (Figure 9)	$\label{eq:VIN} \begin{array}{l} V_{IN} = V_{IL} \text{ or } V_{IH} \\ V_{CH1} \ 1.0 \ V \ \text{or } 4.5 \ V \ \text{with } V_{CH0} \\ \text{floating or} \\ V_{CH1} \ 1.0 \ V \ \text{or } 4.5 \ V \ \text{with } V_{CH1} \\ \text{floating} \\ V_{COM} = 1.0 \ V \ \text{or } 4.5 \ V \end{array}$	I _{COM(ON)}	5.5	1	10	100	nA

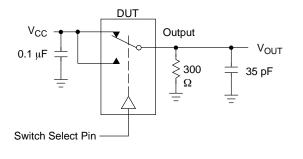
AC ELECTRICAL CHARACTERISTICS (Input $t_r = t_f = 3.0 \text{ ns}$)

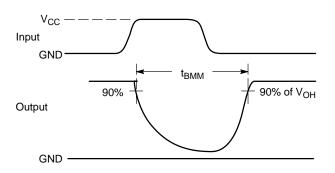
				Guaranteed Max Limit							
			v _{cc}	-5	5 to 25	°C	< 8	5°C	< 12	25°C	
Parameter	Test Conditions	Symbol	(V)	Min	Тур*	Max	Min	Max	Min	Max	Unit
Turn–On Time (Figures 12 and 13) INH to Output	$R_L = 300 \Omega$, $C_L = 35 pF$ (Figures 4 and 5)	t _{ON}	2.5 3.0 4.5 5.5	2 2 1 1	7 5 4 3	12 10 9 8	2 2 1 1	15 15 12 12	2 2 1 1	15 15 12 12	ns
Turn–Off Time (Figures 12 and 13) INH to Output	R_L = 300 Ω, C_L = 35 pF (Figures 4 and 5)	^t OFF	2.5 3.0 4.5 5.5	2 2 1 1	7 5 4 3	12 10 9 8	2 2 1 1	15 15 12 12	2 2 1 1	15 15 12 12	ns
Transition Time (Channel Selec- tion Time) (Figure) Select to Output	$\rm R_L$ = 300 $\Omega,$ $\rm C_L$ = 35 pF (Figures and)	t _{trans}	2.5 3.0 4.5 5.5	5 5 2 2	18 13 12 9	28 21 16 14	5 5 2 2	30 25 20 20	5 5 2 2	30 25 20 20	ns
Minimum Break–Before–Make Time	V_{IS} = 3.0 V (Figure 3) R _L = 300 Ω , C _L = 35 pF	t _{BBM}	2.5 3.0 4.5 5.5	1 1 1	12 11 6 5		1 1 1 1		1 1 1		ns
					Typical	@ 25,	VCC =	= 5.0 V			
Maximum Input Capacitance, Select/INH Input Analog I/O (switch off) Common I/O (switch off) Feedthrough (switch on)		$\begin{array}{c} C_{\rm IN} \\ C_{\rm NO} \text{ or } C_{\rm NC} \\ C_{\rm COM} \\ C_{\rm (ON)} \end{array}$	8 10 10 20					pF			

*Typical Characteristics are at 25°C.

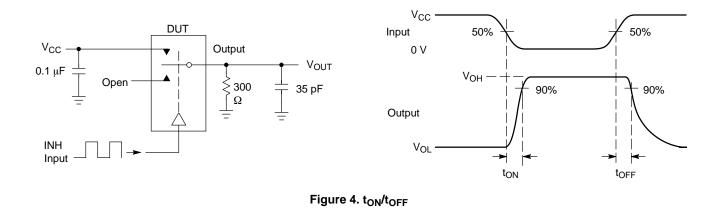
ADDITIONAL APPLICATION CHARACTERISTICS (Voltages Referenced to GND Unless Noted)

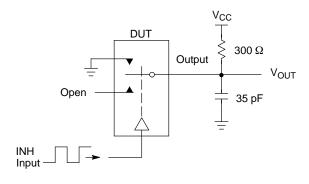
			v _{cc}	Typical	
Parameter	Condition	Symbol	V	25°C	Unit
Maximum On–Channel –3dB Bandwidth or Minimum Frequency Response (Figure 10)	$V_{IN} = 0 \text{ dBm}$ V_{IN} centered between V_{CC} and GND (Figure 7)	BW	3.0 4.5 5.5	170 200 200	MHz
Maximum Feedthrough On Loss	$V_{IN} = 0 \text{ dBm } @ 100 \text{ kHz to 50 MHz}$ V_{IN} centered between V_{CC} and GND (Figure 7)	V _{ONL}	3.0 4.5 5.5	-3 -3 -3	dB
Off–Channel Isolation (Figure 10)	f = 100 kHz; V_{IS} = 1 V RMS V_{IN} centered between V_{CC} and GND (Figure 7)	V _{ISO}	3.0 4.5 5.5	-93 -93 -93	dB
Charge Injection Select Input to Common I/O (Figure 15)		Q	3.0 5.5	1.5 3.0	рС
Total Harmonic Distortion THD + Noise (Figure 14)	F_{IS} = 20 Hz to 100 kHz, RL = Rgen = 600 Ω C_L = 50 pF V_{IS} = 5.0 V_{PP} sine wave	THD	5.5	0.1	%

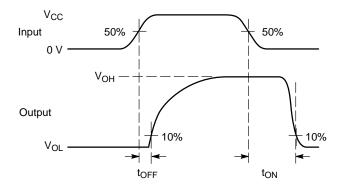


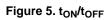












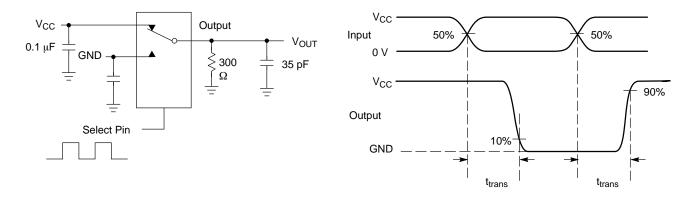
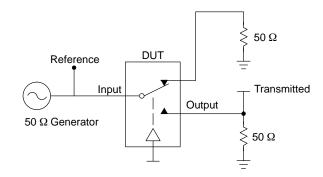


Figure 6. t_{trans} (Channel Selection Time)

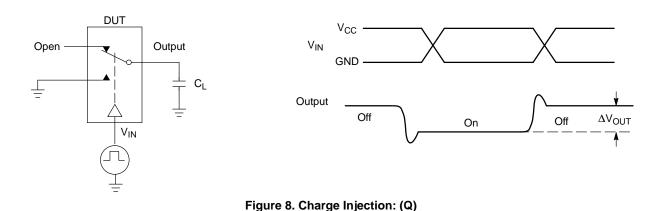


Channel switch control/s test socket is normalized. Off isolation is measured across an off channel. On loss is the bandwidth of an On switch. V_{ISO} , Bandwidth and V_{ONL} are independent of the input signal direction.

$$\begin{split} & \mathsf{V}_{\mathsf{ISO}} = \mathsf{Off} \ \mathsf{Channel} \ \mathsf{Isolation} = \mathsf{20} \ \mathsf{Log} \ \left(\frac{\mathsf{V}\mathsf{OUT}}{\mathsf{VIN}}\right) \ \mathsf{for} \ \mathsf{V}_{\mathsf{IN}} \ \mathsf{at} \ \mathsf{100} \ \mathsf{kHz} \\ & \mathsf{V}_{\mathsf{ONL}} = \mathsf{On} \ \mathsf{Channel} \ \mathsf{Loss} = \mathsf{20} \ \mathsf{Log} \ \left(\frac{\mathsf{V}\mathsf{OUT}}{\mathsf{VIN}}\right) \ \mathsf{for} \ \mathsf{V}_{\mathsf{IN}} \ \mathsf{at} \ \mathsf{100} \ \mathsf{kHz} \ \mathsf{to} \ \mathsf{50} \ \mathsf{MHz} \end{split}$$

Bandwidth (BW) = the frequency 3 dB below VONL

Figure 7. Off Channel Isolation/On Channel Loss (BW)/Crosstalk (On Channel to Off Channel)/V_{ONL}



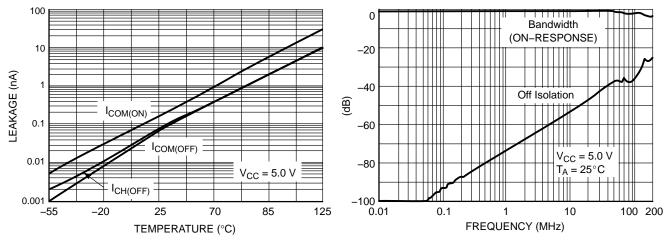
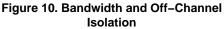
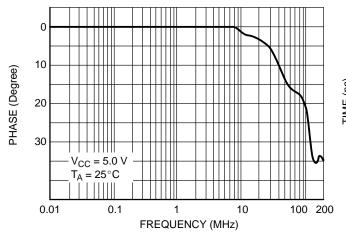
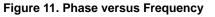


Figure 9. Switch Leakage versus Temperature







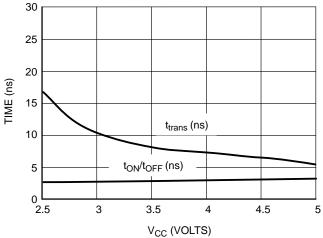


Figure 12. t_{ON} and t_{OFF} versus V_{CC} at 25°C

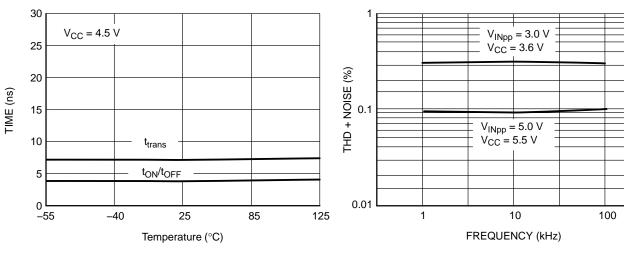
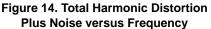
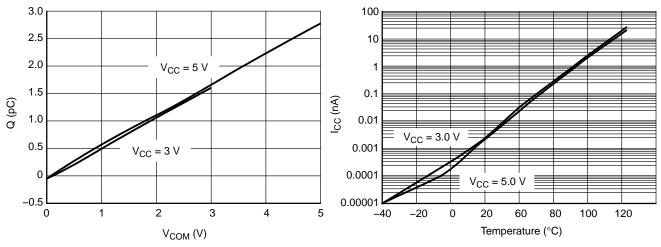


Figure 13. $t_{\mbox{ON}}$ and $t_{\mbox{OFF}}$ versus Temp





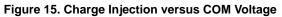


Figure 16. I_{CC} versus Temp, V_{CC} = 3 V & 5 V

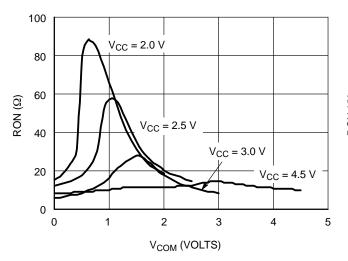


Figure 17. R_{ON} versus V_{COM} and V_{CC (@ 25°C}

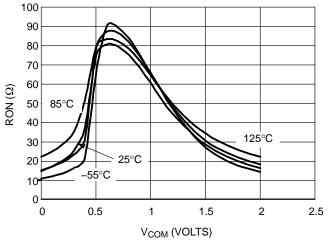
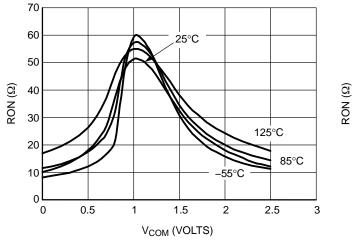
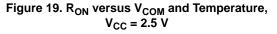
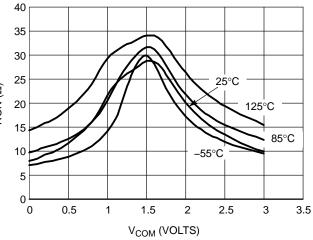
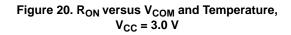


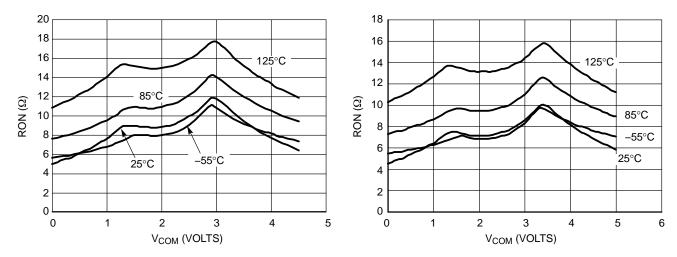
Figure 18. R_{ON} versus V_{COM} and Temperature, V_{CC} 2.0 V











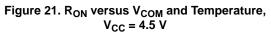


Figure 22. R_{ON} versus V_{COM} and Temperature, V_{CC} = 5.0 V

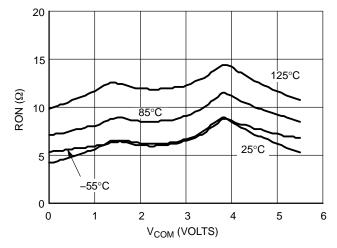
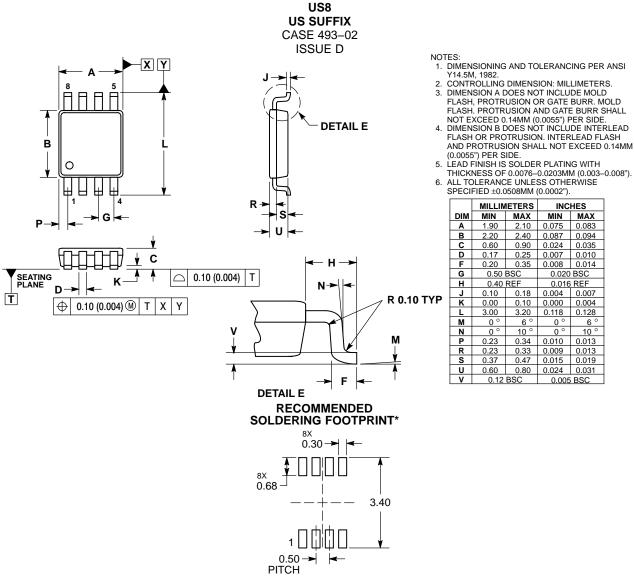


Figure 23. R_{ON} versus V_{COM} and Temperature, V_{CC} = 5.5 V

PACKAGE DIMENSIONS



DIMENSIONS: MILLIMETERS

*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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